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# Infrared spectroscopic detection of the methylsilyl (CH<sub>3</sub>SiH<sub>2</sub>, X<sup>2</sup>A') and the silylmethyl (CH<sub>2</sub>SiH<sub>3</sub>, X<sup>2</sup>A') radicals and their partially deuterated counterparts in low temperature matrices

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#### Abstract

Both the methylsilyl,  $CH_3SiH_2(X^2A')$ , and the silylmethyl,  $SiH_3CH_2(X^2A')$ , together with their partially deuterated isotopomers were identified for the first time via infrared spectroscopy in low temperature silane–methane matrices at 10 K upon exposure of the matrices with mono energetic electrons. Three fundamentals at 654 cm<sup>-1</sup> (v<sub>8</sub>), 1414 cm<sup>-1</sup> (v<sub>12</sub>), and 1251 cm<sup>-1</sup> (v<sub>5</sub>) (methylsilyl) and one absorption at 645 cm<sup>-1</sup> (v<sub>8</sub>) (silylmethyl) were detected; these assignments were confirmed by identifying also partially deuterated radicals through their absorptions at 781 cm<sup>-1</sup> (v<sub>7</sub>), 1415 cm<sup>-1</sup> (v<sub>12</sub>), 1419 cm<sup>-1</sup> (v<sub>4</sub>), and 1546 cm<sup>-1</sup> (v<sub>11</sub>) (d2-methylsilyl,  $CH_3SiD_2$ ) and 582 cm<sup>-1</sup> (v<sub>8</sub>), 749 cm<sup>-1</sup> (v<sub>5</sub>), and 771 cm<sup>-1</sup> (v<sub>13</sub>) (d3-silylmethyl, SiD<sub>3</sub>CH<sub>2</sub>) in d4-silane–methane matrices. Since both silane and methane have been observed in the circumstellar envelope of the carbon star IRC+10216, our investigations assist in future infrared spectroscopic, astronomical searches for these species in interstellar space. Likewise, the knowledge of the infrared absorption features might help to follow the chemical evolution of organo-silicon CVD process via time resolved infrared spectroscopy.

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# 1. Introduction

Small, binuclear organosilane molecules and their radicals of the generic formula  $SiCH_x$  (x = 1-6) are important precursors to prepare amorphous silicon carbide (a-Si–C) films via chemical vapor deposition (CVD) [1,2]. The fully dehydrogenated silicon monocarbide (SiC) is considered as a promising class of materials for high temperature and high power electronic devices since silicon carbide is chemically and mechanically inert and presents a wide-band gap (2.2–2.3 eV) semiconductor [3,4]. In the early years, amorphous silicon carbide films were produced via chemical vapor deposition of mixtures of silicon and carbon bearing gases such as si-

lane (SiH<sub>4</sub>) and methane (CH<sub>4</sub>) [5,6]. Due to the strong carbon–hydrogen bond in the methane molecule, this approach required excessive growth temperatures, often inducing high tensile stress in the silicon carbide films. Recently, the use of single precursor molecules such as methylsilane, CH<sub>3</sub>SiH<sub>3</sub>, has been exploited successfully [7,8]. However, to optimize and even to manipulate the nucleation processes, it is crucial to understand the fundamental, underlying chemical mechanisms in depth. Reaction networks which actual model the chemical vapor deposition processes of organo silanes [9,10] demand crucial input parameters. These are rate constants of the critical reactions involved, the reaction intermediates together with the final reaction products, and their thermochemical data [11–17].

An understanding of the energetics and spectroscopic properties of simple silicon–carbon bearing species is

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also of crucial importance to untangle the elementary chemical reactions involved in circumstellar envelopes of dying carbon stars. About 15% of the observed interstellar molecules contain silicon ranging from simple diatomics (SiC, SiN, SiO, SiS), triatomics (SiCN) and a silicon-terminated cummulene (CCCCSi) to two cyclic species (SiC<sub>2</sub>, SiC<sub>3</sub>) [18,19]. Here, the silane and methane molecules – precursors to more complex organo silicon molecules – have been detected in the outflow of carbon stars [20].

However, despite the importance of the organosilyl molecules as rate limiting growth species of a-Si-C films in chemical vapor deposition processes and their astrophysical potential to form silicon carbide molecules, the vibration levels of the corresponding radicals have not been investigated experimentally. Here, a detailed knowledge of the infrared absorption features might help to follow the chemical evolution of CVD processes in real time not only via mass spectrometry [4], but also through time resolved infrared spectroscopy. Here, the methylsilane (CH<sub>3</sub>SiH<sub>3</sub>;  $\Delta H_{f}^{0} = -31 \text{ kJ mol}^{-1}$ ) molecule as well as the corresponding silvlmethyl CH<sub>2</sub>SiH<sub>3</sub>  $(\Delta H_{\rm f}^0 = 174 \text{ kJ mol}^{-1})$  and methylsilyl CH<sub>3</sub>SiH<sub>2</sub>  $(\Delta H_{\rm f}^0 = 139 \text{ kJ mol}^{-1})$  doublet radicals have received particular attention [21,22]. The spectroscopic properties of the methylsilane molecule  $(CH_3SiH_3)$  have been studied extensively [23], and both microwave [24-27] as well as infrared spectra [28,29] are well known. The bond distances have been determined to be 109.6 nm (CH bond), 148.3 nm (Si-H bond), and 186.9 nm (Si-C bond); the H-C-Si and H-Si-C bond angles were calculated to be 110.9° and 110.5°, respectively. The SiCH<sub>5</sub> radicals are thought to be the key intermediates in the growth of amorphous silicon carbide films. A theoretical study of CVD processes utilizing an ethylsilane  $(C_2H_5SiH_3)$  precursor suggests that the CH<sub>2</sub>SiH<sub>3</sub> species can be formed via a barrier-less methyl radical loss pathway; this process was calculated to be endothermic by  $330 \text{ kJ mol}^{-1}[30]$  and  $371 \text{ kJ mol}^{-1}[31]$ . Recently, the CH<sub>2</sub>SiH<sub>3</sub> and CH<sub>3</sub>SiH<sub>2</sub> radicals were proposed to be formed via methylidene (CH) insertion into a siliconhydrogen bond of silane and silvlidene (SiH) insertion into a carbon-hydrogen bond of methane [32]; both reactions are barrier-less. Alternatively, kinetic studies in the temperature range of 291–1360 K suggest that hydrogen atoms can abstract a hydrogen atom from the methylsilane molecule (CH<sub>3</sub>SiH<sub>3</sub>) via a barrier of about 11 kJ mol<sup>-1</sup>; however, the nature of the SiCH<sub>5</sub> isomer could not be identified since the experiments only follow the decay kinetics of the atomic hydrogen reagent [33-35]. Guided ion beam studies suggest that the enthalpy of formation of the CH<sub>3</sub>SiH<sub>2</sub> radical ranges between 130 and 160 kJ mol<sup>-1</sup> [36]. Note that solely the CH<sub>3</sub>SiH<sub>2</sub> radical was observed in a matrix via ESR at 77 K as a reaction product of vibrationally excited methyl radicals via hydrogen abstraction from neighboring CH<sub>3</sub>SiH<sub>3</sub>; the CH<sub>2</sub>SiH<sub>3</sub> isomer is thermodynamically less stable by 41 kJ mol<sup>-1</sup> and was not observed [37]. Note that a  $^{60}$ Co  $\gamma$  irradiation of methylsilane yielded solely the energetically preferred CH<sub>3</sub>SiH<sub>2</sub> radical [38,39]. Similar to the methylsilane molecule, the infrared [40,41] and millimeter spectra [42] of the closed shell H<sub>2</sub>CSiH<sub>2</sub> species are also known; various theoretical investigations have been carried out on the SiCH<sub>4</sub> potential energy surfaces as well [43,44]. Smaller, hydrogenated silicon-carbon clusters have been investigated, too. For instance, the vibrational levels of the  $H_2CSiH(^2A')$  and  $CH_3Si(^2A'')$  isomers have been determined via negative ion photoelectron spectroscopy [45]. Smith et al. assigned the fundamentals of  $H_2CSi(^1A_1)$  via wavelength resolved fluorescence and stimulated emission pumping (SEP) [46]. The rearrangement to the HCSiH( $^{1}A'$ ) and CSiH<sub>2</sub>( $^{1}A_{1}$ ) isomers has also been probed theoretically [47,48]. Likewise, the vibrational levels and rovibronic spectra of  $HCSi(^{2}\Sigma_{\sigma})$ have been recorded in the gas phase [49,50]. A recent matrix isolation study determined the  $v_1$  mode of the HCSi radical to be at  $1010 \text{ cm}^{-1}$  [51]; this measurement is in close agreement with the gas phase value of  $1013 \text{ cm}^{-1}$  [52] and a theoretical investigation [53].

Despite the importance of the  $SiCH_x$  species in chemical vapor deposition processes and in the chemistry of circumstellar envelopes, the infrared spectroscopic properties of the SiCH<sub>5</sub> radicals are still elusive. This is of particular importance to identify structural isomers and open shell radicals which are thought to be essential growth species in CVD and circumstellar environments. In this paper, we present a combined experimental and theoretical study on the SiCH<sub>5</sub> radical and elucidate for the first time the position of the most intense, hitherto elusive infrared absorption frequencies of the methylsilyl and silylmethyl isomers together with their partially deuterated counterpart in low temperature silane-methane matrices. We demonstrated earlier that an interaction of energetic electrons can cleave a carbon-hydrogen bond in a methane molecule to form atomic hydrogen and a methyl radical at 10 K, reaction (1). Two neighboring methyl radicals were found to recombine forming an ethane molecule (2) [54]. Upon further irradiation with electrons, the ethane molecule decomposes to a hydrogen atom plus an ethyl radical, Eq. (3). In a similar manner, the dilsilyl  $(Si_2H_5)$  radical was synthesized in low temperature silane matrices (reactions (4)-(6)) [55]. Here, we export this concept and attempt to synthesize two SiCH<sub>5</sub> radical isomers via a homologous reaction sequence involving a cross recombination of a methyl with a silvl radical, followed by an atomic hydrogen loss (reactions (7) and (8))

$$CH_4(X^1A_1) \to CH_3(X^2A_2'') + H(^2S_{1/2})$$
 (1)

$$CH_3(X^2A_2'') + CH_3(X^2A_2'') \to C_2H_6(X^1A_{1g})$$
 (2)

Table 1

$$C_2H_6(X^1A_{1g}) \to C_2H_5(X^2A') + H(^2S_{1/2})$$
 (3)

$$SiH_4(X^1A_1) \rightarrow SiH_3(X^2A_1) + H(^2S_{1/2})$$
 (4)

$$SiH_3(X^2A_1) + SiH_3(X^2A_1) \to Si_2H_6(X^1A_{1g})$$
 (5)

$$Si_2H_6(X^1A_{1g}) \rightarrow Si_2H_5(X^2A') + H(^2S_{1/2})$$
 (6)

$$\operatorname{SiH}_{3}(\operatorname{X}^{2}\operatorname{A}_{1}) + \operatorname{CH}_{3}(\operatorname{X}^{2}\operatorname{A}_{2}'') \to \operatorname{CH}_{3}\operatorname{SiH}_{3}(\operatorname{X}^{1}\operatorname{A}_{1})$$
(7)

$$CH_{3}SiH_{3}(X^{1}A_{1}) \rightarrow CH_{3}SiH_{2}/CH_{2}SiH_{3}(X^{2}A') + H(^{2}S_{1/2}).$$
(8)

#### 2. Experimental

The experiments were carried out in a contaminationfree ultrahigh vacuum (UHV) setup consisting of a 15 l cylindrical stainless steel chamber of 250 mm diameter and 300 mm height; this system can be evacuated down to  $8 \times 10^{-11}$  Torr by a magnetically suspended turbopump backed by an oil-free scroll pump [56]. A rotatable, two stage closed cycle helium refrigerator is attached to the lid of the machine and holds a polished silver mono crystal. This crystal is cooled to  $10.2 \pm 0.3$  K and serves as a substrate for the silanemethane ices. The ices were prepared at 10 K by depositing silane (99.99%) and methane (99.99%) at pressures of  $8 \times 10^{-8}$  Torr for 20 min onto the cooled silver crystal. Fig. 1 shows a typical infrared spectrum of the frost at 10 K; all absorptions are summarized in Table 1.

To determine the ice composition and thickness, we integrated the infrared absorption features at 2164 and 883 cm<sup>-1</sup> (silane) as well as 4200, 3852, and 2815 cm<sup>-1</sup> (methane). The ice thicknesses are then calculated via the Lambert–Beers relationship [56]. Considering the integrated absorption coefficients of these fundamentals,



Fig. 1. Infrared spectrum of the silane-methane frost at 10 K. The assignments of the peaks are compiled in Table 1.

Infrared absorptions of the silane-methane ices and their assignments					
Frequency (cm <sup>-1</sup> )	Assignment	Molecule	Frequency (cm <sup>-1</sup> )		
4523	$v_2 + v_3$	CH <sub>4</sub>	4527		
4364	$2v_3$	$SiH_4$	4354		
4358	$v_3 + v_4$	$CH_4$	4349		
4298	$v_3 + v_4$	$CH_4$	4283		
4292	$\nu_1 + \nu_3$	$SiH_4$	4283		
4200	$v_1 + v_4$	$CH_4$	4200		
4112	$v_2 + 2v_4$	$CH_4$	4113		
3852/3895	$3v_4$	$CH_4$	3891/3851		
-	$\nu_3+\nu_4+\beta$	$SiH_4$	3142 (sh)		
3139	$v_2 + v_3$	$SiH_4$	3128		
-	$\nu_3+\nu_4+\alpha$	$SiH_4$	3087		
3074	$v_3 + v_4$	$SiH_4$	3060		
3011	V <sub>3</sub>	$CH_4$	3000		
2815	$v_2 + v_4$	$CH_4$	2815		
2595	$2v_4$	$CH_4$	2595		
2306	$v_3 + \gamma$	$SiH_4$	2300		
-	$v_3 + \beta$	$SiH_4$	2250		
2193	$v_3 + \alpha$	$SiH_4$	2195		
2164	V3	$SiH_4$	2163		
1878	$\nu_2+\nu_4+\alpha$	$SiH_4$	1876		
1300	$v_4$	$CH_4$	1293		
1032	$v_2 + \beta/v_4 + \gamma$	$SiH_4$	1050		
1032	$v_2 + \beta/v_4 + \gamma$	$SiH_4$	1050		
961	V2	$SiH_4$	957		
930	$\nu_4 + \beta$	$SiH_4$	948		
914	$\nu_4 + \alpha$	$SiH_4$	918		
883	$v_4$	$SiH_4$	876		

 $\alpha$ ,  $\beta$ , and  $\gamma$  denote lattice modes of the silane sample; the peak positions in the pure methane and silane samples are shown in column four for comparison [55].

i.e.,  $2.5 \times 10^{-17}$  cm and  $2.0 \times 10^{-17}$  cm (silane) as well as  $1.6 \times 10^{-18}$  cm,  $2.0 \times 10^{-19}$  cm, and  $2.3 \times 10^{-18}$  cm (methane), this gives column densities of  $2.0 \pm 0.1 \times 10^{17}$  cm<sup>2</sup> and  $1.5 \pm 0.2 \times 10^{17}$  cm<sup>2</sup>, respectively. Taking the densities of the silane and methane ices to  $0.77 \pm 0.03$  and  $0.53 \pm 0.02$  g cm<sup>-3</sup> [57], this translates into thicknesses of  $140 \pm 15$  nm silane and  $70 \pm 20$  nm methane, respectively. To confirm the assignments of the methylsilyl and silylmethyl radicals we also conducted irradiations of d4-silane–methane mixtures at 10 K (SiD<sub>4</sub>:CH<sub>4</sub> =  $1.3 \pm 0.1$ :1; thicknesses:  $130 \pm 10 \text{ nm}$  d4-silane and  $65 \pm 10 \text{ nm}$  methane).

To understand the fine structure of the infrared features of the binary ice mixture, it is important to comment briefly on the modifications of the pure solids. At 10 K, methane ice exists in a low-temperature cubic phase II. The carbon atoms of the methane molecules form a cubic close-packed structure for each octant; each unit cell has a lattice constant  $a_0 = 11.68$  Å and contains 32 methane molecules [58]. This results in a well-defined fine structures and lattice vibrations ( $v_L = 56 \pm 2 \text{ cm}^{-1}$ ) superimposed on the  $v_3$  and  $v_4$  fundamentals at  $v_3 + v_L = 3058 \text{ cm}^{-1}$  and  $v_4 + v_L =$ 1348 cm<sup>-1</sup>. At 10 K, silane crystallizes in a tetragonal unit cell ( $a_0 = b_0 = 12.5$  Å;  $c_0 = 14.2$  Å) which contains 32 silane molecules [59]. The infrared spectrum of crystalline silane shows distinct lattice modes (Table 1). We can compare this information with the infrared spectrum of the binary ice mixture (Fig. 1 and Table 1). Here, the lattice vibration of the methane crystal is not present. On the other hand, the  $\alpha$ ,  $\beta$ , and  $\gamma$  lattice modes of silane are still visible. This suggests that we have a solid solution of methane in silane; considering the similar lattice constants, each silane molecule can be replaced by a methane molecule. However, the visible lattice modes of silane crystals in our solid ices. All together, these data imply an overall excess of silane compared to methane in our binary ices; this has been confirmed experimentally finding that the ratio of silane versus methane column densities is  $1.3 \pm 0.2$ .

Our ices were irradiated at 10 K with 5 keV electrons generated in an electron gun at beam currents of 100 nA by scanning the electron beam over an area of  $3.0 \pm 0.4$  cm<sup>2</sup>. Accounting for irradiation times of 60 min and the extraction efficiency of 78.8% of the electrons, this exposes the target to  $1.8 \times 10^{15}$  electrons. To guarantee an identification of the reaction products in the ices and those subliming into the gas phase on line and in situ, a Fourier transform infrared spectrometer (FTIR; solid state) and a quadrupole mass spectrometer (QMS; gas phase) were utilized. The Nicolet 510 DX FTIR spectrometer  $(5000-500 \text{ cm}^{-1})$  operates in an absorption-reflection-absorption mode (reflection angle  $\alpha = 75^{\circ}$ ). The infrared beam is coupled via a mirror flipper outside the spectrometer, passes through a differentially pumped potassium bromide (KBr) window, is attenuated in the ice sample prior and after reflection at a polished silver waver, and exits the main chamber through a second differentially pumped KBr window before being monitored via a liquid nitrogen cooled detector. The gas phase is monitored by a quadrupole mass spectrometer (Balzer QMG 420; 1–200 amu mass range) with electron impact ionization of the neutral molecules in the residual gas analyzer mode.

# 3. Theoretical approach

We have employed the hybrid density functional B3LYP method [60] with the 6-311G(d,p) basis functions in order to obtain the optimized structures and vibrational frequencies for SiCH<sub>x</sub> (x = 5,6) systems. The relative energies are calculated by using the coupled cluster CCSD(T) method [61,62] with the aug-cc-pVTZ basis functions [63] at the structures obtained by the B3LYP method with the correction of B3LYP zeropoint vibrational energies without scaling. All calculations were carried out with GAUSSIAN 98 program package [64]. In order to analyze the infrared spectra for the species obtained by present experiments, we have also calculated the vibrational frequencies and infrared intensities for the CH<sub>3</sub>SiH<sub>3</sub>, CH<sub>3</sub>SiH<sub>2</sub>, CH<sub>2</sub>SiH<sub>3</sub>, and for the partially deuterated species as shown in Table 2.

# 4. Computational results

Fig. 2 shows the optimized structures of  $SiCH_6$  and SiCH<sub>5</sub> systems. The staggered conformation of CH<sub>3</sub>SiH<sub>3</sub> is located at the energy minimum; the eclipsed conformation is the transition state of internal rotation around the carbon-hydrogen bond. This energy barrier of  $6 \text{ kJ mol}^{-1}$  is much smaller than the rotation barrier around the carbon-carbon bond in ethane. The structure  $CH_3SiH_2(X^2A')$  is very similar to the structure of methylsilane. Since the bond strength of Si-H is weaker than that of C–H bond, the  $CH_3SiH_2(X^2A')$  isomer calculated with CCSD(T) method is shown to be 39 kJ mol<sup>-1</sup> more stable than the CH<sub>2</sub>SiH<sub>3</sub>( $X^2A'$ ) isomer. This energy difference is smaller than the values obtained with previous Hartree-Fock [65] and MP2 [66] calculations, but is excellent agreement with the experimental value of  $37 \text{ kJ mol}^{-1}$ . While the SiH<sub>2</sub> moiety of methylsilyl radical  $CH_3SiH_2(X^2A')$  maintains nonplanarity, the radical center of silvlmethyl  $CH_2SiH_3(X^2A')$ has a sp<sup>2</sup> hybridized carbon; a gentle conjugation between p-orbital of carbon atom and Si-H bond makes C-Si bond (1.850 Å) slightly shorter than that of  $CH_3SiH_2$  (1.885 Å) species. The structure of the planar  $sp^2$  hybridized conformation of the SiH<sub>2</sub> moiety of methylsilyl radical is shown to be the transition state of the inversion of the SiH<sub>2</sub> and its energy barrier is calculated to be  $26 \text{ kJ mol}^{-1}$ . Note that we were unable to locate any hydrogen-bridged structure which presents a local minimum on the potential energy surface of SiCH<sub>5</sub> system. Both methylsilyl and silvlmethyl radicals are connected via a transition state of the hydrogen migration as shown in Fig. 2 located 194 kJ mol<sup>-1</sup> above the methylsilyl radical. This barrier height correlates nicely with a previous calculation of  $178 \text{ kJ mol}^{-1}$  and an experimental study of 171 kJ mol<sup>-1</sup> [65]. Note that the energy barrier of internal rotation of methylsilyl and silylmethyl radicals are smaller than that of methylsilane. The eclipsed conformation of methylsilyl radical is less stable by  $4 \text{ kJ mol}^{-1}$  than the staggered conformer, while there is no energy difference between staggered and eclipsed conformations in the silylmethyl radical.

Also, we calculated the energetics for the reactions with the CCSD(T) method, summarized in Fig. 3 (the corresponding B3LYP energies are given in parentheses). The dissociation of the methane and silane molecules into the corresponding methyl and silyl radicals plus atomic hydrogen according to Eqs. (1) and (4) was calculated to be endoergic by 371 (370) kJ mol<sup>-1</sup> and 427 (428) kJ mol<sup>-1</sup>. The recombination of the methyl with the silyl radical is barrier-less and exoergic by 353

Table 2

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Table 2												
Unscaled y	vibrational frequencie	$(cm^{-1})$	) and infrared	intensities	(cm molecule <sup>-1</sup>	) of	CH <sub>3</sub> SiH <sub>3</sub> ,	CH <sub>3</sub> SiD <sub>3</sub> ,	CH <sub>3</sub> SiH <sub>2</sub> ,	CH <sub>3</sub> SiD <sub>2</sub> ,	CH <sub>2</sub> SiH <sub>3</sub> ,	and
CH <sub>2</sub> SiD <sub>3</sub> c	alculated with B3LY	?/6-311G	i(d,p) level of t	heory								

Mode		Characterization	Frequency	Intensity	Frequency	Intensity
			Staggered CH <sub>3</sub> S	iH <sub>3</sub>	Staggered CH <sub>3</sub> Si	D <sub>3</sub>
$\nu_1$	$a_1$	CH <sub>3</sub> sym. stretch	3031	1.10E - 18	3032	1.10E - 18
$v_2$	$a_1$	SiH <sub>3</sub> sym. stretch	2221	1.15E - 17	1581	7.30E - 18
V3	$a_1$	CH <sub>3</sub> umbrella	1305	2.49E - 18	1304	1.89E – 18
$v_4$	$a_1$	SiH <sub>3</sub> umbrella	949	3.95E - 17	736	2.19E - 17
$v_5$	$a_1$	C–Si stretch	690	1.79E – 18	646	2.84E - 18
$v_6$	a <sub>2</sub>	Torsion	194	0.00E + 00	178	0.00E + 00
$\nu_7$	e	CH <sub>3</sub> asym. stretch	3105	3.54E - 18	3105	1.69E – 18
$\nu_8$	e	SiH <sub>3</sub> asym. stretch	2221	4.84E - 17	1605	1.44E – 17
V9	e	CH <sub>3</sub> deformation	1469	1.48E - 18	1468	9.51E – 19
$\nu_{10}$	e	SiH <sub>3</sub> deformation	965	1.58E - 17	692	4.65E - 18
$v_{11}$	e	CH <sub>3</sub> , SiH <sub>3</sub> rocking	896	2.26E - 17	851	6.77E – 18
V <sub>12</sub>	e	CH <sub>3</sub> , SiH <sub>3</sub> rocking	525	3.80E - 18	416	1.45E - 18
			Staggered CH <sub>3</sub> S	iH <sub>2</sub>	Staggered CH <sub>3</sub> Si	$D_2$
$\nu_1$	a′	CH <sub>3</sub> asym. stretch	3091	1.16E - 18	3091	1.15E – 18
$v_2$	a′	CH <sub>3</sub> sym. stretch	3021	1.15E - 18	3021	1.16E – 18
V <sub>3</sub>	a′	SiH <sub>2</sub> sym. stretch	2178	1.45E – 17	1558	8.57E – 18
$\nu_4$	a'	CH <sub>3</sub> deformation	1463	9.78E - 19	1463	1.02E - 18
$v_5$	a'	CH <sub>3</sub> umbrella	1291	1.27E - 18	1291	9.08E - 19
$\nu_6$	a'	SiH <sub>2</sub> bending	938	1.66E - 17	708	9.86E - 18
$\nu_7$	a'	CH <sub>3</sub> , SiH <sub>2</sub> rocking	851	1.31E - 17	811	8.74E – 18
$\nu_8$	a′	C–Si stretch	681	2.85E - 18	643	1.61E – 18
V9	a′	CH <sub>3</sub> , SiH <sub>2</sub> rocking	570	2.54E - 18	450	2.60E - 18
$v_{10}$	a″	CH <sub>3</sub> asym. stretch	3112	1.32E - 18	3112	1.27E - 18
$v_{11}$	a″	SiH <sub>2</sub> asym stretch	2203	2.60E - 17	1594	1.44E - 17
v <sub>12</sub>	a″	CH <sub>3</sub> deformation	1458	1.23E - 18	1458	1.40E - 18
V <sub>13</sub>	a″	$CH_3$ , $SiH_2$ deformation	895	7.23E - 18	851	4.82E - 18
$v_{14}$	a″	$CH_3$ , $SiH_2$ deformation	530	8.87E - 19	413	7.62E - 19
$v_{15}$	a″	Torsion	177	5.55E - 20	155	2.71E - 20
			Staggered CH <sub>2</sub> S	iH <sub>3</sub>	Staggered CH <sub>2</sub> Si	$D_3$
$\nu_1$	a′	CH <sub>2</sub> sym. stretch	3122	7.69E - 19	3122	7.79E – 19
$v_2$	a′	SiH <sub>3</sub> sym. stretch	2221	1.24E - 17	1568	8.02E - 18
V3	a'	SiH <sub>3</sub> asym. stretch	2185	1.89E - 17	1591	1.12E – 17
$v_4$	a′	CH <sub>2</sub> bending	1405	3.66E - 19	1404	1.52E - 19
$v_5$	a′	SiH <sub>3</sub> umbrella	951	3.56E - 17	768	1.53E – 17
$v_6$	a′	SiH <sub>3</sub> deformation	948	1.05E - 17	682	6.69E - 18
$v_7$	a′	C-Si stretching	748	2.19E - 18	672	7.70E - 18
$\nu_8$	a′	SiH <sub>3</sub> rocking	666	1.65E – 17	606	1.30E - 17
V9	a′	CH <sub>2</sub> umbrella	525	1.01E - 18	436	2.25E - 19
$v_{10}$	a″	CH <sub>2</sub> asym. stretch	3214	5.86E - 19	3214	5.58E - 19
$v_{11}$	a″	SiH <sub>3</sub> asym. stretch	2224	2.22E - 17	1607	1.33E - 17
v <sub>12</sub>	a″	SiH <sub>3</sub> deformation	961	7.27E - 18	689	3.97E - 18
v <sub>13</sub>	a″	CH <sub>2</sub> , SiH <sub>3</sub> rocking	847	1.03E - 17	795	6.18E - 18
$v_{14}$	a″	CH <sub>2</sub> , SiH <sub>3</sub> rocking	526	1.58E - 18	423	1.45E - 18
V15	a″	Torsion	17	4.98E - 22	15	8.97E - 22

(331) kJ mol<sup>-1</sup>, whereas the fragmentation of the silicon– hydrogen and carbon–hydrogen bonds to form the methylsilyl radical CH<sub>3</sub>SiH<sub>2</sub>(X<sup>2</sup>A') plus a hydrogen atom and the silylmethyl CH<sub>2</sub>SiH<sub>3</sub>(X<sup>2</sup>A') plus atomic hydrogen from methylsilane requires 375 (367) kJ mol<sup>-1</sup> and 414 (404) kJ mol<sup>-1</sup>, respectively. The overall energetics to form silylmethyl CH<sub>2</sub>SiH<sub>3</sub>(X<sup>2</sup>A') and methylsilyl radical CH<sub>3</sub>SiH<sub>2</sub>(X<sup>2</sup>A') via Eq. (9) was calculated to be +859 and +820 kJ mol<sup>-1</sup>. These values agree very well with those derived from enthalpies of formation as listed in [21,22] and in the NIST database [67].

$$\begin{split} & CH_4(X^1A_1) + SiH_4(X^1A_1) \\ & \to H_2SiCH_3/H_3SiCH_2(X^2A') + 3H(^2S_{1/2}). \end{split} \tag{9}$$

Tables 2 and 3 summarize the vibrational frequencies and infrared intensities of  $CSiH_6$  and  $CSiH_5$  systems calculated with the B3LYP/6-311G(d,p) level of theory. Table 2 includes the frequencies and intensities of partially deuterated species of methylsilane, silylmethyl, and methylsilyl at their energy minima. Table 3 shows the frequencies located at the transition states which have one imaginary vibrational mode for each species.



Fig. 2. Optimized structures of methylsilane (CH<sub>3</sub>SiH<sub>3</sub>) (staggered and eclipsed; top row) as well as the methylsilyl CH<sub>3</sub>SiH<sub>2</sub>( $X^{2}A'$ ) and silylmethyl CH<sub>2</sub>SiH<sub>3</sub>( $X^{2}A'$ ) radicals together with the transition state involved in the hydrogen migration and the SiH<sub>2</sub> inversion of CH<sub>3</sub>SiH<sub>2</sub> (middle row) calculated with B3LYP/6-311G(d,p) level of theory. The eclipsed conformers of the methylsilyl and silylmethyl radicals are also shown (bottom row). The bond lengths and bond angles are in Angstrom and degrees, respectively. The values in parentheses are the relative energies calculated with the CCSD(T) method.



Fig. 3. Schematic potential energy surface of the reaction of methane with silane to form the methylsilyl radical  $CH_3SiH_2(X^2A')$  and the silylmethyl  $CH_2SiH_3(X^2A')$  radical. Energies have been obtained with the CCSD(T) method; zero point vibrational energies are included. The transition state involved in the hydrogen migration is denoted as a bold, dashed line. The values in parentheses are the relative energies obtained with the B3LYP level of theory.

# 5. Experimental results

Upon irradiation of the silane–methane sample, prominent absorptions of the silyl radical,  $SiH_3(X^2A_1)$ , and of the methyl radical,  $CH_3(X^2A_2'')$ , developed instan-

taneously at 722 and  $609 \text{ cm}^{-1}$ , respectively (Table 4). The positions of both v<sub>2</sub> umbrella modes correlate nicely previous studies utilizing hydrogen, neon, argon, and krypton (721–738 cm<sup>-1</sup>; silyl) [68–70] as well as neon, argon, and nitrogen matrices (603–611 cm<sup>-1</sup>; methyl)

Table 3

Unscaled vibrational frequencies  $(cm^{-1})$  and infrared intensities  $(cm molecule^{-1})$  of the eclipsed conformers of CH<sub>3</sub>SiH<sub>3</sub>, CH<sub>3</sub>SiH<sub>2</sub>, and CH<sub>2</sub>SiH<sub>3</sub> calculated with B3LYP/6-311G(d,p) level of theory

		Characterization	Frequency	Intensity
Eclipsed CH <sub>3</sub> Si	H <sub>3</sub>			
V <sub>1</sub>	a	CH <sub>3</sub> sym. stretch	3040	1.19E – 18
V <sub>2</sub>	a	SiH <sub>3</sub> sym. stretch	2220	1.19E - 17
V3	a	CH <sub>3</sub> umbrella	1309	2.54E - 18
V <sub>4</sub>	a	SiH <sub>3</sub> umbrella	957	3.87E - 17
v <sub>5</sub>	a	C-Si stretching	687	2.68E - 18
V <sub>6</sub>	a	Torsion	190 <i>i</i>	0.00E + 00
ν <sub>7</sub>	e	CH <sub>3</sub> asym. stretch	3111	3.16E - 18
$\nu_8$	e	SiH <sub>3</sub> asym. stretch	2219	4.74E - 17
V9	e	CH <sub>3</sub> deformation	1475	1.32E - 18
$v_{10}$	e	SiH <sub>3</sub> deformation	965	1.69E - 17
$v_{11}$	e	CH <sub>3</sub> , SiH <sub>3</sub> rocking	875	1.76E – 17
v <sub>12</sub>	e	SiH <sub>3</sub> ,CH <sub>3</sub> rocking	575	5.99E – 18
Transition state	between CH <sub>3</sub> SiH <sub>2</sub> and CH <sub>2</sub> SiH <sub>3</sub>			
V1	a'	CH <sub>2</sub> sym. stretch	3129	5.68E - 20
V <sub>2</sub>	a'	SiH <sub>2</sub> sym. stretch	2199	1.39E - 17
V3	a'	SiH stretch	1877	1.96E - 18
V <sub>4</sub>	a'	CH <sub>2</sub> scissor	1375	1.13E - 18
V5	a'	SiH <sub>2</sub> scissor	897	1.62E - 17
V <sub>6</sub>	a'	C–Si stretch	776	2.47E - 18
v <sub>7</sub>	a'	CH <sub>2</sub> , SiH <sub>2</sub> wagging	668	1.41E - 18
v <sub>8</sub>	a'	$CH_2$ , SiH <sub>2</sub> wagging	603	1.33E - 17
Vg	a'	H shift	1725 <i>i</i>	9.35E - 17
V10	a″	CH <sub>2</sub> asym. stretch	3231	3.32E - 19
V11	a″	$SiH_2$ asym. stretch	2238	2.17E – 17
V <sub>12</sub>	a″	H rolling	1003	3.21E - 18
V <sub>13</sub>	a″	CH <sub>2</sub> , SiH <sub>2</sub> rock	828	7.34E - 18
v <sub>14</sub>	a″	CH <sub>2</sub> , SiH <sub>2</sub> rock	532	6.60E - 19
v <sub>15</sub>	a″	$CH_2$ , $SiH_2$ twist	265	9.50E - 21
Eclinsed CH_S	Ha			
Vi	a'	CH <sub>2</sub> asym_stretch	3102	1.06E – 18
V <sub>1</sub>	a′	CH <sub>2</sub> sym_stretch	3032	1.00E = 10 1.22E = 18
V2 V2	a′	SiH <sub>2</sub> sym. stretch	2180	1.22E = 10 1.44E - 17
V4	a'	CH <sub>2</sub> deformation	1459	1.06E - 18
V5	a'	CH <sub>2</sub> umbrella	1294	1.19E – 18
V <sub>6</sub>	a'	SiH <sub>2</sub> scissor	941	1.58E - 17
V7	a'	CH <sub>3</sub> , SiH <sub>2</sub> rock	834	8.94E – 18
V <sub>8</sub>	a'	C–Si stretch	677	3.30E - 18
Vo	a'	SiH <sub>2</sub> umbrella	610	4.39E - 18
V10	a″	$CH_3^2$ asym. stretch	3109	1.17E – 18
V11	a″	$SiH_2$ asym. stretch	2205	2.52E - 17
V <sub>12</sub>	a″	CH <sub>3</sub> deformation	1472	7.53E - 19
V <sub>13</sub>	a″	CH <sub>3</sub> , SiH <sub>2</sub> rocking	854	6.32E - 18
v <sub>14</sub>	a″	SiH <sub>2</sub> ,CH <sub>3</sub> rocking	569	1.42E - 18
V <sub>15</sub>	a″	Torsion	174 <i>i</i>	3.32E - 22
Eclinsed CH_S	<sup>2</sup> H <sub>2</sub>			
Vi	a'	CH <sub>2</sub> asym_stretch	3214	5 67E – 19
V2	a'	CH <sub>2</sub> sym. stretch	3122	7.80E - 19
V <sub>2</sub>	a'	SiH stretch	2231	1.84E - 17
V <sub>4</sub>	a'	SiH <sub>2</sub> sym. stretch	2205	1.31E - 17
V5	a'	CH <sub>2</sub> scissor	1405	3.68E - 19
V6	a'	SiH <sub>3</sub> deformation	961	7.40E - 18
V7	a'	SiH <sub>3</sub> umbrella	951	3.71E – 17
V <sub>8</sub>	a'	CH <sub>2</sub> rocking	847	1.04E - 17
V9	a'	C–Si stretch	748	2.17E - 18
V <sub>10</sub>	a'	CH <sub>2</sub> , SiH <sub>3</sub> rocking	527	1.61E - 18
V <sub>11</sub>	a″	SiH <sub>2</sub> asym. stretch	2195	2.21E - 17
V <sub>12</sub>	a″	SiH <sub>3</sub> deformation	947	8.90E - 18
V <sub>13</sub>	a″	CH <sub>2</sub> inversion, SiH <sub>3</sub> rocking	663	1.64E - 17
v <sub>14</sub>	a″	CH <sub>2</sub> inversion, SiH <sub>3</sub> rocking	526	9.10E - 19
V15	a″	Torsion	61 <i>i</i>	7.37E - 20

The frequencies of the transition state connecting the methylsilyl and the silylmethyl radicals are also included.

Table 4 Compilation of newly observed species and their absorptions in low temperature silane–methane matrices

Frequency (cm <sup>-1</sup> )	Fundamental	Carrier
609	V2	CH <sub>3</sub>
722	V2	$SiH_3$
826	V <sub>12</sub>	$C_2H_6$
1380	V16	$C_2H_6$
1462	$v_{11}$	$C_2H_6$
2880	V5	$C_2H_6$
2973	$v_{10}$	$C_2H_6$
826	V <sub>6</sub>	$Si_2H_6$
934	$v_{11}$	$Si_2H_6$
2142	V <sub>5/4</sub>	$Si_2H_6$
691	V5	CH <sub>3</sub> SiH <sub>3</sub>
863	$v_{11}$	CH <sub>3</sub> SiH <sub>3</sub>
946	$v_{10}$	CH <sub>3</sub> SiH <sub>3</sub>
976	$\nu_4$	CH <sub>3</sub> SiH <sub>3</sub>
1254	V <sub>3</sub>	CH <sub>3</sub> SiH <sub>3</sub>
2142	V2	CH <sub>3</sub> SiH <sub>3</sub>
530	V9	$C_2H_5$
2848	V3	$C_2H_5$
2939	$v_2$	$C_2H_5$
852	V <sub>6</sub>	$Si_2H_5$
654	$\nu_8$	CH <sub>3</sub> SiH <sub>2</sub>
1414	$v_{12}$	CH <sub>3</sub> SiH <sub>2</sub>
1251	V5	CH <sub>3</sub> SiH <sub>2</sub>
645	$\nu_8$	CH <sub>2</sub> SiH <sub>3</sub>

[71]. Note that the umbrella mode holds the highest absorption coefficient  $(1.4 \times 10^{-17} \text{ cm})$ ; the remaining fundamentals  $(v_1(a'_1) \text{ (infrared inactive)}),$  $v_3(e')$  $(1.2 \times 10^{-18} \text{ cm})$ , and  $v_4(e')$   $(6.6 \times 10^{-19} \text{ cm})$  of the methyl radical cannot be observed. The  $v_4$  deformation  $(925-928 \text{ cm}^{-1}; 2.2 \times 10^{-17} \text{ cm})$  [68-70] and the v<sub>3</sub> silicon-hydrogen stretching mode  $(2185 \text{ cm}^{-1};$  $4.3 \times 10^{-17}$  cm) [72] remain unobservable in our experiments because they are obscured by the fundamentals of the silane ice; the infrared intensity of the  $v_1$  mode  $(8.3 \times 10^{-19} \text{ cm})$  is too weak to be observed. Also, absorptions at 826, 1380, 1462, 2880, and 2973 cm<sup>-1</sup> showed up immediately at the beginning of the irradiation. These features were assigned to the  $\nu_{12},\,\nu_{6},\,\nu_{11},$  $v_5$ , and  $v_{10}$  modes of the ethane (C<sub>2</sub>H<sub>6</sub>) molecule; the remaining fundamentals of ethane are infrared inactive. Similarly, we detected the absorptions of the disilane species (Si<sub>2</sub>H<sub>6</sub>) at 826 cm<sup>-1</sup> (v<sub>6</sub>, shoulder), 934 cm<sup>-1</sup> (v<sub>11</sub>), and 2142 cm<sup>-1</sup> (v<sub>5/10</sub>, shoulder). The detection of the MH<sub>3</sub> and  $M_2H_6$  species (M = C, Si) is in perfect agreement with the electron exposure experiments of the neat silane [55] and methane ices [54]. Here, the ethane and disilane molecule were simply the recombination products of two methyl and silyl radicals, respectively (Eqs. (2) and (5)). The spectra of these species have been reported previously [54,55] and are not shown here.

Since ethane and silane could be detected, we would also expect the formation of the methylsilane molecule  $(CH_3SiH_3)$  via cross recombination of a methyl with the silyl radical through Eq. (7). Indeed, we were able to observe new bands appearing instantaneously with the start of the irradiation at 691, 863, 946, 976, 1254, 2142 cm<sup>-1</sup> (Table 4). Two absorptions are shown in Fig. 4. These positions can be assigned to the  $v_5(a_1, C-Si$  stretching),  $v_{11}(e, CH_3 \text{ rocking})$ ,  $v_4(a_1, SiH_3 \text{ sym$  $metric deformation})$ ,  $v_{10}(e, SiH_3$  asymmetric deformation),  $v_3(a_1, CH_3$  symmetric deformation), and  $v_2(a_1, CH_3 \text{ symmetric stretch})$  fundamentals of the methylsilane molecule; note that the 2142 cm<sup>-1</sup> peak is actually composed of two absorptions from methylsilane and from ethane. These data agree very well with our computational studies (Table 2) after scaling by 0.97 – a reasonable value for the B3LYP method – and also with previous experiments [28].



Fig. 4. Top: The absorption feature of the methylsilane molecule at 863 cm<sup>-1</sup> ( $v_{11}$ ). The  $v_6$  mode of the disilyl radical, the  $v_{12}$  absorption of ethane and the  $v_6$  fundamental of disilane (revealed by deconvolution) are also shown. Bottom: Deconvoluted peak consisting of the 1254 cm<sup>-1</sup> absorption of the methylsilane molecule ( $v_3$ ) and the 1250 cm<sup>-1</sup> feature of the methylsilyl radical ( $v_5$ ). Both spectra were taken after 60 min irradiation time.

We could identify also bands at 530, 2848, and 2939 cm<sup>-1</sup> (Table 4); these features agree very well with the CH<sub>2</sub> out of plane (v<sub>9</sub>, a'), CH<sub>3</sub> stretch (v<sub>3</sub>, a'), and CH<sub>3</sub> symmetric stretch (v<sub>2</sub>, a') positions of the ethyl radical (C<sub>2</sub>H<sub>5</sub>) reported previously [73]. Also, these three peaks have the highest infrared absorption coefficients of  $8.3 \times 10^{-18}$  cm,  $5.3 \times 10^{-18}$  cm, and  $4.6 \times 10^{-18}$  cm of the fundamentals of the ethyl radical. Similarly, we were able to observe the disilyl radical (Si<sub>2</sub>H<sub>5</sub>) via its strongest absorption of the umbrella mode at 852 cm<sup>-1</sup>(v<sub>6</sub>, a',  $6.9 \times 10^{-17}$  cm) [55]. Compared to a previous observation in a silane matrix, this position is blue shifted by 9 cm<sup>-1</sup>. Note that the less intense absorptions at about 945 and 2140 cm<sup>-1</sup> overlap with the intensive modes of the methylsilane molecule.

Recall that both the ethyl and disilyl radicals were found to be formal decomposition products of the corresponding closed shell ethane and disilane molecules (Eqs. (3) and (6)). Therefore, we could predict that either the CH<sub>3</sub>SiH<sub>2</sub> and/or the CH<sub>2</sub>SiH<sub>3</sub> radical should be formed via fragmentation of the methylsilane molecule, too. Indeed, we were able to monitor three fundamentals of the methylsilyl radical  $CH_3SiH_2(X^2A')$  at 654 cm<sup>-1</sup>  $(v_8)$ , 1414 cm<sup>-1</sup> $(v_{12})$ , and 1251 cm<sup>-1</sup> $(v_5$ ; shoulder) as shown in Table 4. These observed frequencies are in very good agreement with our calculations (Table 2) predicting – after scaling by a factor of 0.97 – peak positions at 660, 1414, and 1252  $\text{cm}^{-1}$ . Most importantly, the intensity ratio of the  $v_8$  versus  $v_{12}$  fundamentals of  $(2.7 \pm 0.1)$ :1 correlate very well with the theoretically predicted one of  $(2.3 \pm 0.5)$ :1. The peak at 1414 cm<sup>-1</sup>  $(v_{12})$  is weaker. As the irradiation time increases, a shoulder developed at the low frequency site of the  $v_8$ absorption; a deconvolution routine utilizing Gaussian peak profiles yielded a second peak at  $645 \text{ cm}^{-1}$ (Fig. 5). This could be assigned to the  $v_8$  of the silvlmethyl radical  $CH_2SiH_3(X^2A')$ ; theory predicts – after scaling by 0.97-646 cm<sup>-1</sup>. Accounting for the absorption coefficients of the 660 and the 645 cm<sup>-1</sup> fundamentals, we derived a ratio of the methylsilyl versus silylmethyl radical concentration at the end of the irradiation of  $(22 \pm 3)$ :1, i.e., a preferential formation of the thermodynamically more stable isomer.

To confirm these assignments, we prepared d4-silanemethane ices  $(SiD_4-CH_4)$  and subjected this mixture also to a 5 keV electron irradiation – hoping to synthesize partially deuterated  $CH_3SiD_2(X^2A')$  and/or  $CH_2SiD_3(X^2A')$  radicals. As expected, we observed besides the methyl and ethyl radicals, the perdeuterated silyl radical via its v<sub>2</sub> absorption at 541 cm<sup>-1</sup> (Table 5). Also, prominent peaks are visible at 606 and 1541 cm<sup>-1</sup>, which could be attributed to the perdeuterated disilane molecule; a prominent absorption also emerges at 625 cm<sup>-1</sup> (perdeutero disilyl radical). These positions are in excellent agreement with previous irradiation exposures of pure d4-silane samples at 10 K [55]. Fig. 5. Top: Absorption of the methylsilyl radical,  $CH_3SiH_2(X^2A')$ , at 654 cm<sup>-1</sup> ( $v_8$ ) after 10 min irradiation time. Bottom: Deconvoluted absorptions of the methylsilyl radical,  $CH_3SiH_2(X^2A')$ , at 654 cm<sup>-1</sup> ( $v_8$ ) and of the silylmethyl radical,  $CH_2SiH_3(X^2A')$ , at 645 cm<sup>-1</sup> ( $v_8$ ) after 60 min irradiation time.

Most importantly, we were also able to assign six fundamentals of the d3-methylsilane molecule (CH<sub>3</sub>SiD<sub>3</sub>) (Table 5) – a potential precursor to form the d2-methylsilyl radical and/or the d3-silylmethyl species at 10 K. It is also worth mentioning that we see additional features at 1167 and  $684 \text{ cm}^{-1}$ . Comparing these absorptions with literature values of partially deuterated methane and silane molecules [74] suggests that these peaks can be attributed to the  $v_4$  fundamentals of the CH<sub>3</sub>D and SiD<sub>3</sub>H molecules, respectively. The identification of these species is important evidence that upon electron exposure of the d4-silane and methane molecules, the latter undergo initially carbon-hydrogen and silicondeuterium bond rupture processes to form the spectroscopically observed methyl and d3-silyl radicals; the deuterium and hydrogen atoms are mobile at 10 K and can also cross recombine with the methyl radical and the d3-silvl radical to synthesize CH<sub>3</sub>D and SiD<sub>3</sub>H molecules, respectively, via Eqs. (10) and (11):



Table 5 Compilation of newly observed species and their absorptions in low temperature d4-silane-methane matrices

Frequency (cm <sup>-1</sup> )	Fundamental	Carrier
1167	$v_4$	CH <sub>3</sub> D
684	$v_4$	SiD <sub>3</sub> H
541	V <sub>2</sub>	$SiD_3$
606	V6	$Si_2D_6$
1541	V <sub>5</sub>	$Si_2D_6$
640	V5	CH <sub>3</sub> SiD <sub>3</sub>
735	$v_4$	CH <sub>3</sub> SiD <sub>3</sub>
1253	V <sub>3</sub>	CH <sub>3</sub> SiD <sub>3</sub>
1410	V9	CH <sub>3</sub> SiD <sub>3</sub>
1583	$v_8$	CH <sub>3</sub> SiD <sub>3</sub>
2923	$v_1$	CH <sub>3</sub> SiD <sub>3</sub>
625	V <sub>6</sub>	$Si_2D_5$
781	V7	CH <sub>3</sub> SiD <sub>2</sub>
1415	V <sub>12</sub>	$CH_3SiD_2$
1419	$v_4$	$CH_3SiD_2$
1546	V <sub>11</sub>	CH <sub>3</sub> SiD <sub>2</sub>
582	$v_8$	$CH_2SiD_3$
749	V5	CH <sub>2</sub> SiD <sub>3</sub>
771	$v_{13}$	$CH_2SiD_3$

The absorptions of the methyl radical, ethane, and the ethyl radical are shifted by up to  $3 \text{ cm}^{-1}$  compared to the silane–methane matrix (Table 4) and are not reported here.

$$CH_3(X^2A_2'') + D(^2S_{1/2}) \to CH_3D(X^1A_1)$$
 (10)

$$SiD_3(X^2A_1) + H(^2S_{1/2}) \to SiD_3H(X^1A_1).$$
 (11)

Most importantly, we were also able to observe four fundamentals of the doubly deuterated methylsilyl radical (CH<sub>3</sub>SiD<sub>2</sub>) at 781, 1415, 1419, and 1546 cm<sup>-1</sup>(Table 5). These data are in excellent agreement with our calculated frequencies predicting – after scaling by 0.97 – absorptions at 786, 1414, 1419, and 1546 cm<sup>-1</sup> (Table 2). Likewise, the second isomer, the d3-silylmethyl radical, could be also confirmed experimentally via its bands at 582, 749, and 771 cm<sup>-1</sup>. Here, these values also agree very well with the computed frequencies (588, 745, 771 cm<sup>-1</sup>) (Tables 2 and 5).

### 6. Discussion and summary

Our results suggest that the response of the silanemethane target upon electron irradiation is shaped initially by silicon-hydrogen and carbon-hydrogen bond rupture processes in the silane and methane molecules, respectively. This leads to the synthesis of the silyl radical,  $SiH_3(X^2A_1)$ , and the methyl radical,  $CH_3(X_2A''_2)$ , plus atomic hydrogen via Eqs. (1) and (4). However, each hydrogen atom demands an excess energy – the lattice binding energy – of a few tens of kJ mol<sup>-1</sup> to escape from the initially formed [SiH<sub>3</sub>…H] and matrix cages [CH<sub>3</sub>…H] [75]. If this energy cannot be supplied, the hydrogen atom will react back with the silyl and methyl radicals to 'recycle' silane and methane. The presence of mobile hydrogen atoms during the irradiation is supported by two findings. First, the detection of singly hydrogenated silane,  $SiD_3H(X^1A_1)$ , and singly deuterated methane,  $CH_3D(X^1A_1)$ , during the exposure of d4-silane-methane targets to electrons strongly indicates the reaction of mobile hydrogen atoms with d3-silyl and of mobile deuterium atoms with methyl radicals according to Eqs. (10) and (11), respectively. Second, our mass spectrometric data also verify the formation of mobile hydrogen atoms in the ice at 10 K (Fig. 6). The ion current of m/e = 2 (H<sub>2</sub>) increase sharply as the electron beam is switched on and reaches quickly a plateau. As the irradiation is stopped after 60 min, the m/e = 2 signal decreases quickly. Since we were unable to identify any  $SiH_x$  or  $CH_x$  species in the solid state except the silvl and methyl radicals, we can conclude that the molecular hydrogen is formed via recombination of two hydrogen atoms in the ice. It should be stressed that m/e = 2 present the only signal detected with the mass spectrometer during the irradiation of the ices. This indicates that the molecular hydrogen in the gas phase does not represent a fragment from any hydrogenated silicon and/or carbon bearing molecules. Note that similar to pure silane experiments, the mass spectrometric data also show that after the irradiation, the matrix stores thermalized hydrogen atoms; these atoms diffuse upon warming the matrix (here at 14 K) and recombine to molecular hydrogen. The latter is being released into the gas phase (Fig. 6).

How can our data explain the formation of the methylsilane and the hitherto elusive silylmethyl and methylsilyl radicals? Recall that each electron can release its kinetic energy via multiple energy transfers to various silane and methane molecules. Utilizing the CASINO code [76], we find that each 5 keV electron loses  $0.7 \pm 0.1$  keV of its kinetic energy while penetrating



Fig. 6. Temporal profile of the methane (m/e = 16; bottom) and molecular hydrogen (m/e = 2; bottom) evolution during the irradiation (60 min), the isothermal phase at 10 K (30 min), and the heating of the silane–methane sample.

the methane-silane target; this corresponds to an averaged electronic energy transfer of  $3.3 \pm 0.5 \text{ keV } \mu \text{m}^{-1}$ . Also, since the dissociation energy of the Si-H and C-H bonds are 376 kJ mol<sup>-1</sup> (3.9 eV) and 439 kJ mol<sup>-1</sup> (4.5 eV) [77,78], each electron can form up to 180 silvl and 155 methyl radicals in the matrix. Considering the composition of the matrix, 100 silyl and about 70 methyl radicals should be generated statistically per implanted electron. Due to the immobility of silvl and methyl radicals at 10 K, only *neighboring* radicals can recombine to form disilane, ethane, and methylsilane inside the trajectory at 10 K. Note that the formed methylsilane molecule is initially vibrationally excited. This internal energy can be either diverted via phonon coupling to the matrix thus stabilizing the methylsilane molecule (as detected via infrared spectroscopy), fragments back to the silyl and methyl radical, or loses a hydrogen atom thus releasing the excess energy predominantly as kinetic energy of the hydrogen atom. In this case, the vibrationally excited methylsilane molecule should undergo either a Si-H or C-H bond cleavage to form the methylsilyl and the silvlmethyl radical. Based on our experiments, we only detect the methylsilyl radical with the onset of the electron irradiation. This suggests a preferential rupture of the Si-H bond in the vibrationally excited methylsilane species; this correlates nicely with inherent bond strengths (Fig. 3) and also with  $^{60}$ Co  $\gamma$  irradiation of methylsilane vielding solely the energetically preferred CH<sub>3</sub>SiH<sub>2</sub> radical [38,39]. Here, the Si-H bond is 39 kJ mol<sup>-1</sup> weaker than the C–H bond – making it easier to dissociate to the methylsilyl than to the silylmethyl radical. However, as the irradiation time increases, we see additional features of the silylmethyl radical. This could be explained by a radiolysis of the methylsilane molecule, i.e., a decomposition of the methylsilane molecule upon energy transfer by the energetic electron followed by decomposition to methylsilyl and silvlmethyl. Our scenario postulates that at the end of the irradiation, we should have formed an excess of methylsilyl compared to silvlmethyl radicals; this has been confirmed experimentally by observing a methylsilyl versus silvlmethyl ratio of  $22 \pm 3$ . For completeness, we would like to address briefly the possibility of silicon and carbon atoms reacting with methane and silane molecules. Maier et al. [41] observed that at 10 K, silicon atoms did not react with methane via insertion due to an inherent entrance barrier. Likewise, the reaction of ground state carbon atoms is prohibited since an entrance barrier blocks this pathway [19]. Most important, these reactions would lead to SiCH<sub>4</sub> isomers which were clearly not observed in our experiment. Note that a reaction of free silicon and carbon atoms with mobile hydrogen atoms in our matrix is also expected to form simple silicon hydrides such as SiH and SiH<sub>2</sub> as well as CH and CH<sub>2</sub> through barrier-less recombination reactions, which in turn could react with methane and silane via

insertion processes. However, we would like to recall that this represents a time-delayed multi-step reaction mechanism which could not account for the prompt observation of methylsilane upon onset of the irradiation. Finally, we were unable to observe the well-known infrared features of SiH, SiH<sub>2</sub>, CH, and CH<sub>2</sub> [67]; these considerations suggest that the reactions of small carbon and silicon hydrogenated molecules can be likely ruled out.

Summarized, we presented the very first infrared spectroscopic detection of two hitherto elusive SiCH<sub>5</sub> species, i.e., the methylsilyl  $CH_3SiH_2(X^2A')$  and silylmethyl  $CH_2SiH_3(X^2A')$  radicals, together with their partially deuterated counterparts. Since both the methane and silane precursors are present in the circumstellar envelope of the carbon star IRC+10216, the  $v_8$ ,  $v_{12}$ , and  $v_5$  $(CH_3SiH_2)$  as well as v<sub>8</sub>  $(CH_2SiH_3)$  fundamentals can now be utilized to search for these species in the circumstellar shell with powerful infrared telescopes. Note that the computed dipole moments of 0.739 Debye (CH<sub>3</sub>SiH<sub>3</sub>; A = 56.119 GHz, B = C = 10.821 GHz, 0.806 Debye $(CH_3SiH_2, A = 73.007 GHz, B = 11.583 GHz, C =$ 11.027 GHz), and 0.650 Debye (CH<sub>2</sub>SiH<sub>3</sub>, A =67.012 GHz, B = 11.952 GHz, C = 11.475 GHz) suggest that an infrared spectroscopic detection of these species is actually more likely than an identification via radio telescopes. In addition, the presented infrared frequencies help to follow the time-dependent concentration profiles of crucial organo-silane species – here both the methylsilyl and the silvlmethyl radicals – in real time in chemical vapor deposition to ultimately optimize these processes.

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